



Patent No. RDID0075US

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: HAAR, Hans-Peter et al.

Application No.: 09/896,965

Group No.: 1743

Filed: June 29, 2001

Examiner: To Be Assigned

For: TEST ELEMENT ANALYSIS SYSTEM

Assistant Commissioner for Patents
Washington, D.C. 20231

TRANSMITTAL OF CERTIFIED COPY OF PRIORITY DOCUMENT

Attached please find the certified copy of the foreign application from which priority is claimed for this case:

Country: Germany

Application Number: 100 32 015.5

Filing Date: 1 July 2000

Respectfully submitted,

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Date: June 3, 2002

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CERTIFICATE OF MAILING BY "EXPRESS MAIL" (37 CFR 1.10) Applicant(s): <u>HAAR, Hans-Peter et al.</u>		Docket No. <u>#5</u> RDID0075US	
Serial No. 09/896,965	Filing Date June 29, 2001	Examiner To Be Assigned	Group Art Unit 1743
Invention: <u>TEST ELEMENT ANALYSIS SYSTEM</u>			

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